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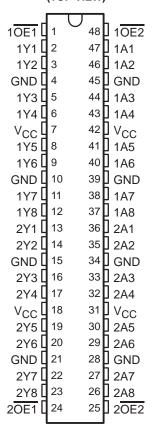
- **Members of the Texas Instruments** Widebus™ Family
- State-of-the-Art *EPIC-IIB™* BiCMOS Design Significantly Reduces Power Dissipation
- Latch-Up Performance Exceeds 500 mA Per **JEDEC Standard JESD-17**
- Typical V_{OLP} (Output Ground Bounce) < 1 V at $V_{CC} = 5 \text{ V}, T_A = 25^{\circ}\text{C}$
- Distributed V_{CC} and GND Pin Configuration Minimizes High-Speed Switching Noise
- Flow-Through Architecture Optimizes PCB Layout
- High-Drive Outputs (-32-mA I_{OH}, 64-mA I_{OI})
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL), Thin Shrink Small-Outline (DGG), and Thin Very Small-Outline (DGV) Packages, and 380-mil Fine-Pitch Ceramic Flat (WD) Package **Using 25-mil Center-to-Center Spacings**

description

The SN54ABT16540 and SN74ABT16540A are inverting 16-bit buffers/drivers composed of two 8-bit sections with separate output-enable gates. These buffers and bus drivers provide a high-performance bus interface for wide data paths.

The 3-state control gate is a 2-input AND gate with active-low inputs so that if either output-enable $(\overline{OE1} \text{ or } \overline{OE2})$ input is high, all corresponding outputs are in the high-impedance state.

SN54ABT16540 . . . WD PACKAGE SN74ABT16540A...DGG, DGV, OR DL PACKAGE (TOP VIEW)



To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN54ABT16540 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74ABT16540A is characterized for operation from -40°C to 85°C.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

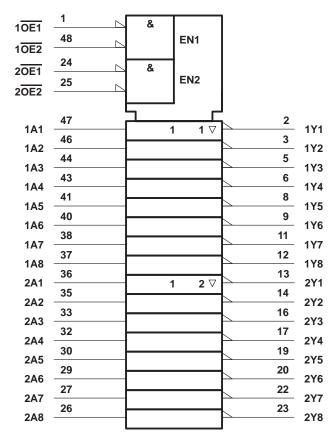
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FUNCTION TABLE (each 8-bit section)

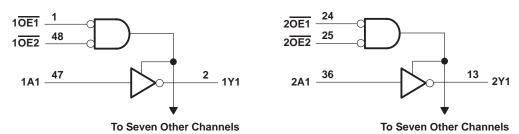
	INPUTS	OUTPUT	
OE1	OE2	Α	Y
L	L	L	Н
L	L	Н	L
Н	X	Χ	Z
Х	Н	Χ	z

logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)





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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	0.5 V to 7 V
Input voltage range, V _I (see Note 1)	$-0.5\;V$ to 7 V
Voltage range applied to any output in the high or power-off state, VO	\dots –0.5 V to 5.5 V
Current into any output in the low state, IO: SN54ABT16540	96 mA
SN74ABT16540A	128 mA
Input clamp current, I _{IK} (V _I < 0)	–18 mA
Output clamp current, I _{OK} (V _O < 0)	–50 mA
Package thermal impedance, θ _{JA} (see Note 2): DGG package	89°C/W
DGV package	93°C/W
DL package	94°C/W
Storage temperature range, T _{stq}	65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions (see Note 3)

				Γ16540	SN74ABT16540A		UNIT
			MIN	MAX	MIN	MAX	UNII
Vcc	V _{CC} Supply voltage				4.5	5.5	V
V _{IH} High-level input voltage				EM	2		V
V _{IL}	L Low-level input voltage			0.8		0.8	V
٧ _I	V _I Input voltage			Vcc	0	VCC	V
loh	I _{OH} High-level output current			-24		-32	mA
loL	Low-level output current	200	48		64	mA	
Δt/Δν	Input transition rise or fall rate	Outputs enabled	BA	10		10	ns/V
TA	Operating free-air temperature		-55	125	-40	85	°C

NOTE 3: Unused inputs must be held high or low to prevent them from floating.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

^{2.} The package thermal impedance is calculated in accordance with EIA/JEDEC Std JESD51.

SN54ABT16540, SN74ABT16540A 16-BIT BUFFERS/DRIVERS WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		T _A = 25°C			SN54ABT16540		SN74ABT16540A		UNIT	
PARA	MEIER	TEST CONDITIONS		MIN	TYP†	MAX	MIN	MAX	MIN	MAX	UNII	
VIK		V _{CC} = 4.5 V,	I _I = -18 mA			-1.2		-1.2		-1.2	V	
		$V_{CC} = 4.5 \text{ V},$	$I_{OH} = -3 \text{ mA}$	2.5			2.5		2.5			
\/a		$V_{CC} = 5 V$,	$I_{OH} = -3 \text{ mA}$	3			3		3		٧	
VOH	VOH	VCC = 4.5 V	I _{OH} = -24 mA	2			2					
		VCC = 4.5 V	$I_{OH} = -32 \text{ mA}$	2*					2			
VOL		V _{CC} = 4.5 V	$I_{OL} = 48 \text{ mA}$			0.55		0.55			V	
VOL		VCC = 4.5 V	$I_{OL} = 64 \text{ mA}$			0.55*				0.55	V	
V _{hys}					100						mV	
IĮ		$V_{CC} = 5.5 \text{ V},$	$V_I = V_{CC}$ or GND			±1		<u></u> ±1		±1	μΑ	
lozh		$V_{CC} = 5.5 \text{ V},$	$V_0 = 2.7 \text{ V}$			10		50		10	μΑ	
lozL		$V_{CC} = 5.5 \text{ V},$	$V_0 = 0.5 V$			-10	-5 0			-10	μΑ	
l _{off}		$V_{CC} = 0$,	V_I or $V_O \le 4.5 \text{ V}$			±100		ζ		±100	μΑ	
ICEX		V _{CC} = 5.5 V, V _O = 5.5 V	Outputs high			50	Singo	50		50	μΑ	
IO [‡]		V _{CC} = 5.5 V,	V _O = 2.5 V	-50	-100	-180	– 50	-180	-50	-180	mA	
		V _{CC} = 5.5 V, I _O = 0, V _I = V _{CC} or GND	Outputs high			3		2		3		
Icc			Outputs low			34		32		34	mA	
			Outputs disabled			3		2		3		
	Data inputs		Outputs enabled			1		1		1	mA	
ΔICC§ Co			Outputs disabled			0.05		0.05		0.05		
	Control inputs	V _{CC} = 5.5 V, One input at 3.4 V, Other inputs at V _{CC} or GND				1.5		1.5		1.5		
Ci		V _I = 2.5 V or 0.5 V	V _I = 2.5 V or 0.5 V		3.5						pF	
Co		V _O = 2.5 V or 0.5 V			7.5						pF	

^{*} On products compliant to MIL-PRF-38535, this parameter does not apply.

switching characteristics over recommended ranges of supply voltage and operating free-air temperature, $C_L = 50$ pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 5 V, T _A = 25°C			SN54ABT16540		SN74ABT16540A		UNIT
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
^t PLH	A	Y	1	2.3	3.3	1	4.2	1	4.1	ns
^t PHL			1.1	2.5	4.1	1.1	4.4	1.1	4.3	
^t PZH	ŌĒ	Y	1.1	3.1	4.2	1.1	5.2	1.1	5.1	ns
^t PZL			1.6	3.7	4.8	1.6	6	1.6	5.9	
^t PHZ	ŌĒ	Y	1.6	4	5	01.6	5.4	1.6	5.7	ne
t _{PLZ}			1.4	3.2	4.4	1.4	4.7	1.4	4.7	ns

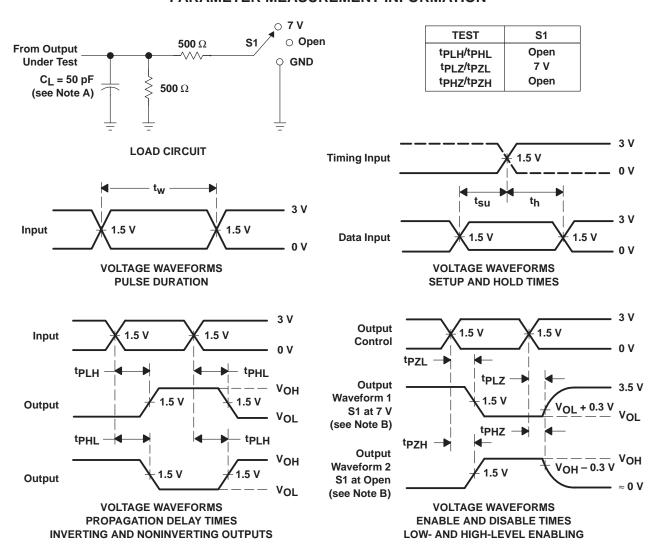


[†] All typical values are at $V_{CC} = 5 \text{ V}$.

[‡] Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

[§] This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50~\Omega$, $t_f \leq$ 2.5 ns, $t_f \leq$ 2.5 ns.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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